

RECEIVED
AUG 16 2001
TC 3700 MAIL ROOM

APPENDIX C

(CLEAN VERSION OF ALL PENDING CLAIMS)

(Serial No. 09/708,932)



CLAIMS RECEIVED

What is claimed is:

A1

As

AUG 16 2001

1. (Amended) A mold apparatus for forming at least ine fine at bump for direct placement on bond pads on a secondary substrate, comprising:
a substrate having a surface;
at least one cavity formed in said surface of said substrate; and
a nonstick protective layer applied to said at least one cavity.

- 2. (Amended) The mold apparatus according to claim 1, wherein said nonstick protective layer is a silicon oxide layer.
- 3. (Amended) The mold apparatus according to claim 1, wherein said nonstick protective layer is a silicon nitride layer.
- 4. (Amended) The mold apparatus according to claim 1, wherein said nonstick protective layer prevents metal material from adhering to said at least one cavity.
 - 5. The mold apparatus according to claim 4, wherein said metal material is a solder paste comprising lead and nickel.
 - 6. The mold apparatus according to claim 1, wherein said at least one cavity has a depth in said surface of said substrate of about 28 micrometers.
 - 7. (Amended) The mold apparatus according to claim 1, wherein said nonstick protective layer has a thickness ranging from about 200 Angstroms to 5 micrometers.
 - 8. The mold apparatus according to claim 1, wherein said at least one cavity has a trapezoidal shape.

- The mold apparatus according to claim 1, wherein said at least one cavity has a hemispherical shape.
- 10. The mold apparatus according to claim 1, wherein said at least one cavity has a rectangular shape.
- 11. The mold apparatus according to claim 1, wherein said at least one cavity has a square shape.
- 12. The mold apparatus according to claim 1, further comprising: at least one heating strip located on another surface of said substrate.
- 13. The mold apparatus according to claim 1, further comprising: a plurality of heating strips located on another surface of said substrate.
- 14. The mold apparatus according to claim 12, further comprising: an electrical conductor connected to a portion of the at least one heating strip.
- 15. The mold apparatus according to claim 13, further comprising: an electrical conductor connected to a portion of the plurality of heating strips.
- 16. The mold apparatus according to claim 1, wherein said substrate comprises semiconductor material.
- 17. The mold apparatus according to claim 1, wherein said substrate comprises ceramic material.

13

18. (Amended) A solder mold apparatus for forming at least one metal bump for direct placement on a corresponding bond pad on a secondary substrate, comprising: a substrate having a surface;

Site

at least one cavity formed in said surface of said substrate; a nonstick protective layer applied to said at least one cavity; and a metal paste applicator.

- 19. (Amended) The solder mold apparatus according to claim 18, wherein said nonstick protective layer is a silicon oxide layer.
- 20. (Amended) The solder mold apparatus according to claim 18, wherein said nonstick protective layer is a silicon nitride layer.

21. (Amended) The solder mold apparatus according to claim 18, wherein said nonstick protective layer prevents metal material from adhering to said at least one cavity.

- 22. The solder mold apparatus according to claim 21, wherein said metal material is a solder paste comprising lead and nickel.
- 23. The solder mold apparatus according to claim 22, further comprising a metal paste dispenser, coupled to said metal paste applicator, to place a metal paste on said substrate.
- 24. The solder mold apparatus according to claim 23, further comprising a heating element to melt said metal paste to form a contact for application to said secondary substrate.
- 25. The solder mold apparatus according to claim 18, wherein said at least one cavity has a depth in said surface of said substrate of about 28 micrometers.

- A4 26. (Amended) The solder mold apparatus according to claim 18, wherein said nonstick protective layer has a thickness ranging from above 200 Angstroms to 5 micrometers.
 - 27. The solder mold apparatus according to claim 18, wherein said substrate comprises semiconductor material.
 - 28. The solder mold apparatus according to claim 18, wherein said substrate comprises a ceramic material.

29. (Amended) A mold apparatus for forming at least one metal bump for direct placement on bond pads on a secondary substrate, comprising: a substrate having a surface;

A5

at least one cavity formed in said surface of said substrate, said at least one cavity having a selected width and a selected length in said surface; and a nonstick protective layer applied to said at least one cavity.

- 30. (Amended) The mold apparatus according to claim 29, wherein said nonstick protective layer is a silicon oxide layer.
- 31. (Amended) The mold apparatus according to claim 29, wherein said nonstick protective layer is a silicon nitride layer.
- 32. (Amended) The mold apparatus according to claim 29, wherein said nonstick protective layer prevents metal material from adhering to said at least one cavity.
- 33. The mold apparatus according to claim 32, wherein said metal material is a solder paste comprising lead and nickel.

- 34. The mold apparatus according to claim 29, wherein said at least one cavity has a depth in said surface of said substrate of about 28 micrometers.
- 35. (Amended) The mold apparatus according to claim 29, wherein said nonstick protective layer has a thickness ranging from about 200 Angstroms to 5 micrometers.
 - 36. The mold apparatus according to claim 29, wherein said selected width and said selected length are substantially the same.
 - 37. The mold apparatus according to claim 29, wherein said selected width is smaller than said selected length.
 - 38. The mold apparatus according to claim 29, wherein said at least one metal bump has substantially the same dimensions as said at least one cavity.
 - 39. The mold apparatus according to claim 29, further comprising: at least one heating strip located on another surface of said substrate.
 - 40. The mold apparatus according to claim 29, further comprising: a plurality of heating strips located on another surface of said substrate.
 - 41. The mold apparatus according to claim 29, wherein said substrate comprises semiconductor material.